A5G37H110N Airfast RF Power GaN Transistor

Rev. 0 — January 2022

This 13.5 W asymmetrical Doherty RF power GaN transistor is designed for cellular base station applications requiring very wide instantaneous bandwidth capability covering the frequency range of 3600 to 3800 MHz.

This part is characterized and performance is guaranteed for applications operating in the 3600 to 3800 MHz band. There is no guarantee of performance when this part is used in applications designed outside of these frequencies.

3700 MHz

 Typical Doherty Single-Carrier W-CDMA Reference Circuit Performance: V_{DD} = 48 Vdc, I_{DQA} = 70 mA, V_{GSB} = -4.0 Vdc, P_{out} = 13.5 W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. ⁽¹⁾

Frequency	G _{ps} (dB)	ղը (%)	Output PAR (dB)	ACPR (dBc)
3600 MHz	15.1	54.1	8.1	-29.5
3700 MHz	15.4	53.5	8.4	-31.8
3800 MHz	15.3	54.3	8.3	-32.0

1. All data measured in reference circuit with device soldered to printed circuit board.

Features

- High terminal impedances for optimal broadband performance
- Improved linearized error vector magnitude with next generation signal
- Able to withstand extremely high output VSWR and broadband operating conditions
- · Designed for low complexity analog or digital linearization systems
- Optimized for massive MIMO active antenna systems for 5G base stations



Data Sheet: Technical Data

Note: Exposed backside of the package is the source terminal for the transistor.

Figure 1. Pin Connections



Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	125	Vdc
Gate-Source Voltage	V _{GS}	-8, 0	Vdc
Operating Voltage	V _{DD}	55	Vdc
Maximum Forward Gate Current, $I_{G (A+B)} @ T_{C} = 25^{\circ}C$	I _{GMAX}	13.3	mA
Storage Temperature Range	T _{stg}	−65 to +150	°C
Case Operating Temperature Range	T _C	-55 to +150	°C
Maximum Channel Temperature	Т _{СН}	225	°C

Table 2. Recommended Operating Conditions

Rating	Symbol	Value	Unit
Operating Voltage	V _{DD}	48	Vdc

Table 3. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 133°C, P _D = 14.7 W	R _{θJC} (IR)	2.7 (1)	°C/W
Thermal Resistance by Finite Element Analysis, Channel-to-Case Case Temperature 133°C, P _D = 14.7 W	R _{0CHC} (FEA)	6.1 (2)	°C/W

Table 4. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JS-001-2017)	1B
Charge Device Model (per JS-002-2014)	C3

Table 5. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD22-A113, IPC/JEDEC J-STD-020	3	260	°C

Table 6. Electrical Characteristics (T_A = 25°C unless otherwise noted)

Characteristic		Min	Тур	Max	Unit
Off Characteristics ⁽³⁾		•			
				2.1 3.9	mAdc
On Characteristics — Side A, Carrier					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 4.6 \text{ mAdc})$	V _{GS(th)}	-4.6	-3.0	-1.9	Vdc
Gate Quiescent Voltage $(V_{DD} = 48 \text{ Vdc}, I_{DA} = 70 \text{ mAdc}, \text{Measured in Functional Test})$	V _{GSA(Q)}	-3.0	-2.5	-2.0	Vdc
Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc)	I _{GSS}	-2.1	_	_	mAdc
On Characteristics — Side B, Peaking					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 8.7 \text{ mAdc})$	V _{GS(th)}	-4.6	-3.0	-1.9	Vdc
Gate-Source Leakage Current (V _{DS} = 150 Vdc, V _{GS} = -8 Vdc)	I _{GSS}	-3.9	_	_	mAdc

1. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to http://www.nxp.com/RF and search for AN1955.

 R_{θCHC} (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated by the expression MTTF (hours) = 10^[A + B/(T + 273)], where *T* is the channel temperature in degrees Celsius, *A* = -11.6 and *B* = 9129.

3. Each side of device measured separately.

(continued)

Table 6. Electrical Characteristics (T_A = 25°C unless otherwise noted) (continued)

Characteristic	Symbol	Min	Тур	Max	Unit
Functional Tests ⁽¹⁾ (In NXP Doherty Production Test Fixture, 50 ohm sy P _{out} = 12.6 W Avg., f = 3700 MHz, 1–tone CW. [See note on correct bia			70 mA, V _{GSE}	₃ = (V _t – 1.55)	Vdc,
Power Gain	G _{ps}	12.0	15.1	18.0	dB
Drain Efficiency	η _D	38.0	42.9	_	%
Pout @ 6 dB Compression Point	P6dB	46.0	47.8	_	dBm
Wideband Ruggedness ⁽²⁾ (In NXP Doherty Reference Circuit, 50 ohm sy White Gaussian Noise (AWGN) with 10 dB PAR	/stem) I _{DQA} = 7	70 mA, V _{GSB}	= -4.0 Vdc, f	= 3700 MHz, /	Additive
ISBW of 400 MHz at 55 Vdc, 25 W Avg. Modulated Output Power (3 dB Input Overdrive from 0.4 W Avg. Modulated Output Power)		No E	evice Degrad	lation	
Typical Performance ⁽²⁾ (In NXP Doherty Reference Circuit, 50 ohm sys 3600–3800 MHz Bandwidth	em) V _{DD} = 48	Vdc, I _{DQA} = 7	′0 mA, V _{GSB} =	= -4.0 Vdc,	
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW _{res}	—	250		MHz
	VBW _{res} G _F		250 0.26		MHz dB
(IMD Third Order Intermodulation Inflection Point)					
(IMD Third Order Intermodulation Inflection Point) Gain Flatness in 200 MHz Bandwidth @ P _{out} = 13.5 W Avg.					
(IMD Third Order Intermodulation Inflection Point) Gain Flatness in 200 MHz Bandwidth @ P _{out} = 13.5 W Avg. Fast CW, 27 ms Sweep	G _F		0.26		dB
(IMD Third Order Intermodulation Inflection Point) Gain Flatness in 200 MHz Bandwidth @ P _{out} = 13.5 W Avg. Fast CW, 27 ms Sweep P _{out} @ 6 dB Compression Point AM/PM (Maximum value measured at the P6dB compression point across	G _F P6dB		0.26		dB W

Table 7. Ordering Information

Device	Tape and Reel Information	Package
A5G37H110NT4	T4 Suffix = 2,500 Units, 16 mm Tape Width, 13-inch Reel	DFN 7 × 6.5

1. Part internally input matched.

2. All data measured in reference circuit with device soldered to printed circuit board.

NOTE: Correct Biasing Sequence for GaN Depletion Mode Transistors in a Doherty Configuration

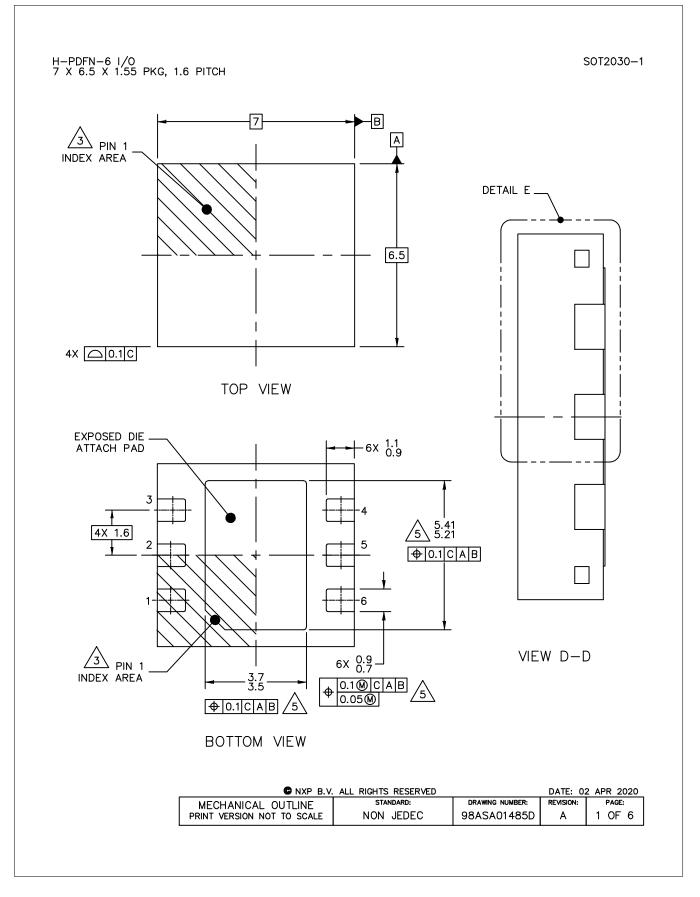
Bias ON the device

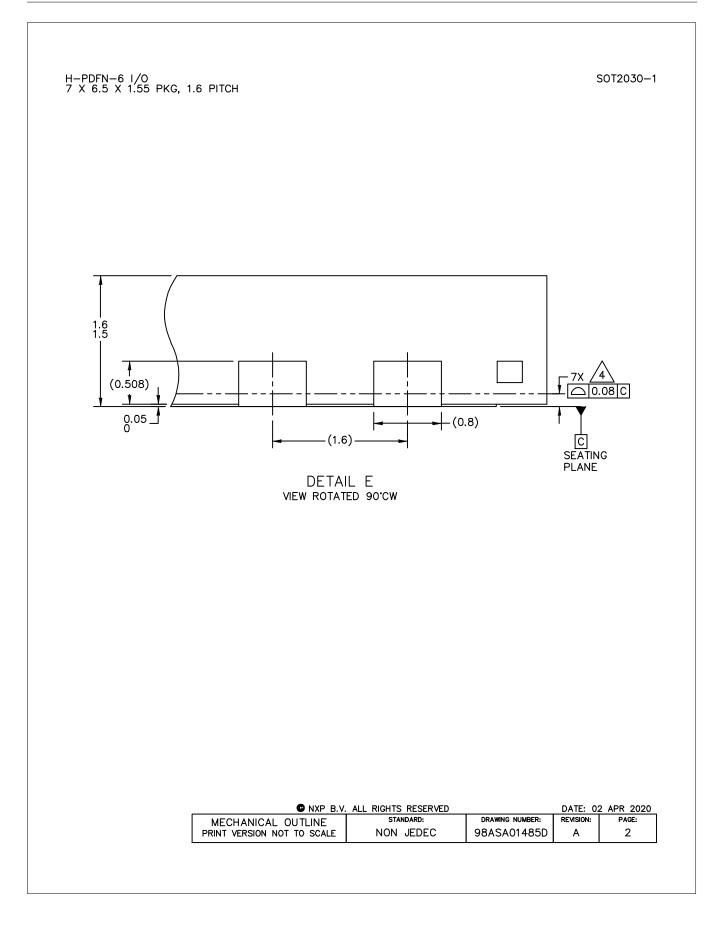
- 1. Set gate voltage V_{GSA} and V_{GSB} to –5 V.
- 2. Set drain voltage V_{DSA} and V_{DSB} to nominal supply voltage (+48 V).
- 3. Increase V_{GSA} (carrier side) until I_{DQA} current is attained.
- 4. Increase V_{GSB} (peaking side) to target bias voltage.
- 5. Apply RF input power to desired level.

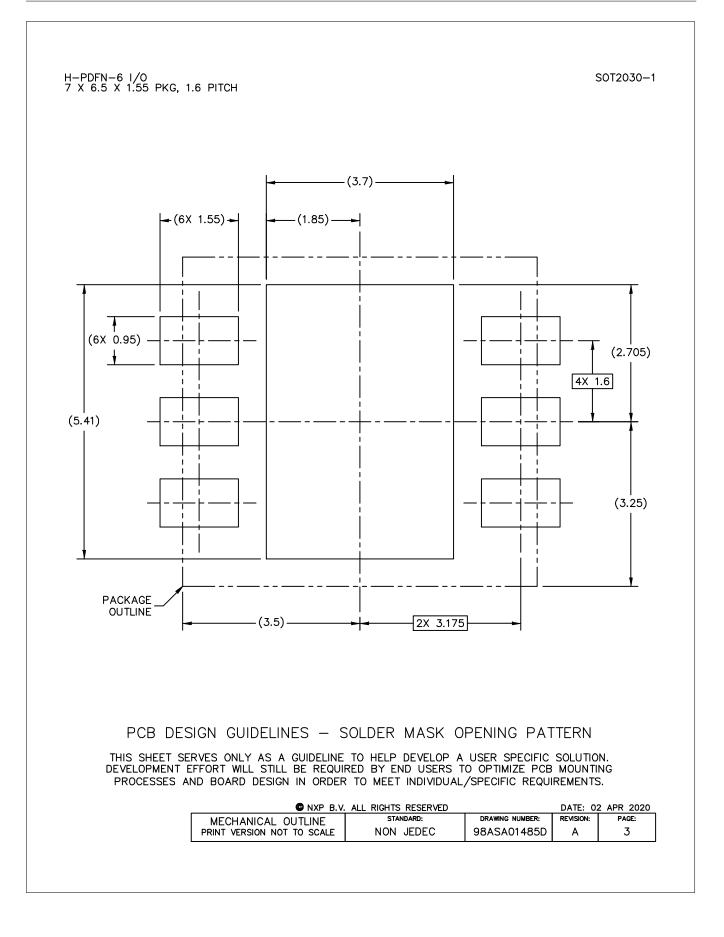
Bias OFF the device

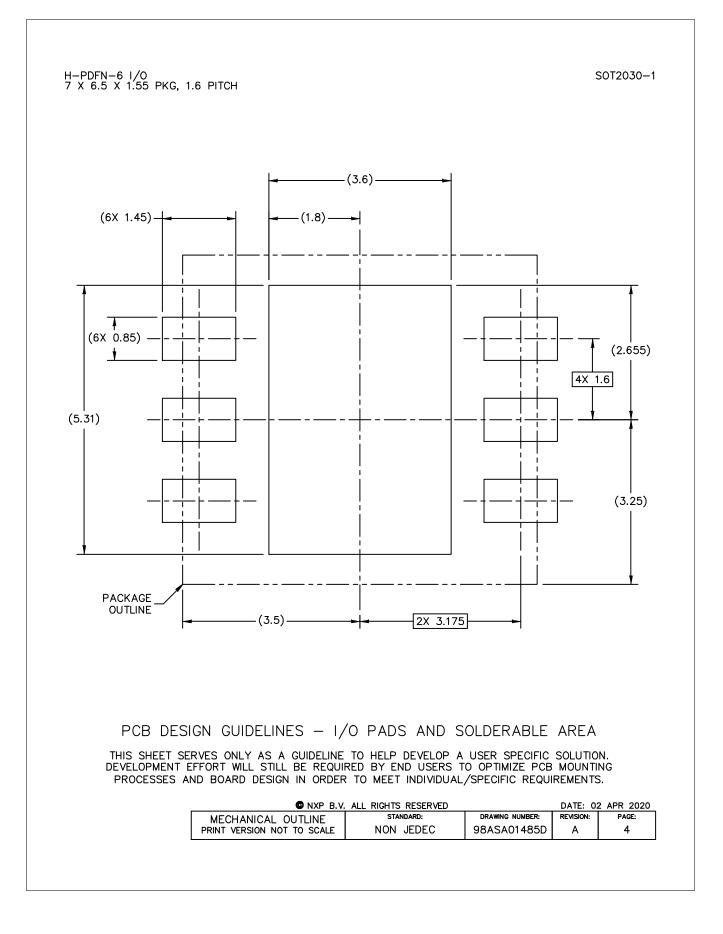
- 1. Disable RF input power.
- 2. Adjust gate voltage V_{GSA} and V_{GSB} to –5 V.
- Adjust drain voltage V_{DSA} and V_{DSB} to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Disable V_{GSA} and V_{GSB} .

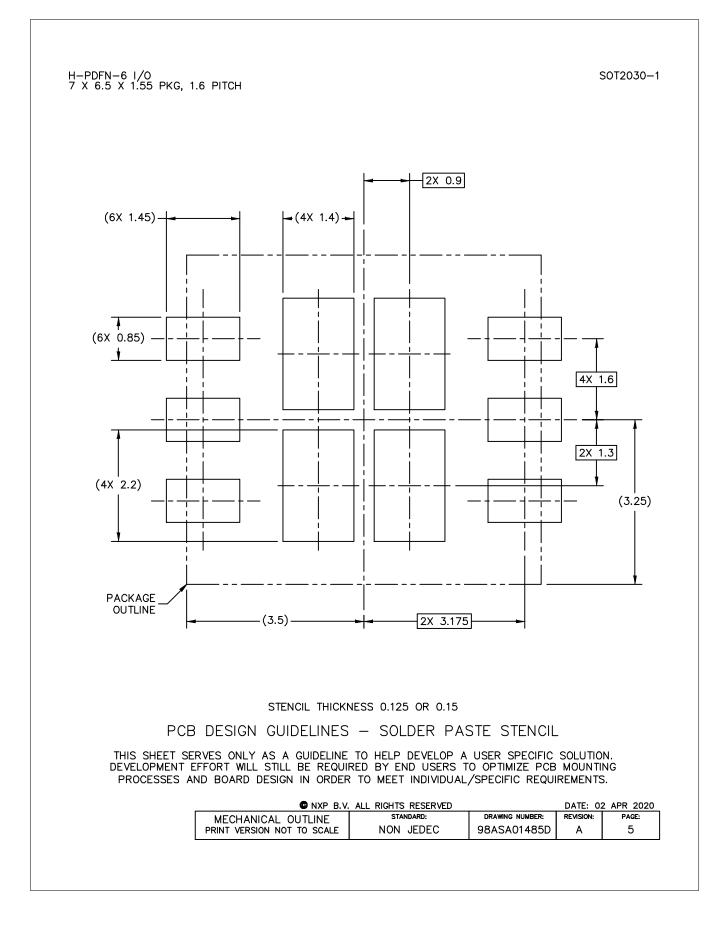
Package Information











H-PDFN-6 I/O 7 X 6.5 X 1.55 PKG, 1.6 PITCH

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- /3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.
- 4. COPLANARITY APPLIES TO LEADS AND DIE ATTACH FLAG.

5. RADIUS ON LEAD AND DIE ATTACH FLAG IS OPTIONAL.

NXP B.V. ALL RIGHTS RESERVED DATE: 02 APR 2020				
MECHANICAL OUTLINE	standard:	drawing number:	REVISION:	PAGE:
PRINT VERSION NOT TO SCALE	NON JEDEC	98ASA01485D	A	6

Product Documentation and Software

Refer to the following resources to aid your design process.

Application Notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Software

.s2p File

Revision History

The following table summarizes revisions to this document.

Revision	Date	Description
0	Jan. 2022	Initial release of data sheet